SoftMC

A Flexible and Practical Open-Source Infrastructure for Enabling Experimental DRAM Studies

Presented at HPCA 2017

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Executive Summary

- Two critical problems of DRAM: **Reliability** and **Performance**
  - Recently-discovered bug: *RowHammer*
- ***Characterize***, ***analyze***, and ***understand*** DRAM cell behavior
- We design and implement **SoftMC**, an FPGA-based DRAM testing infrastructure
  - Flexible and Easy to Use (C++ API)
  - Open-source (*github.com/CMU-SAFARI/SoftMC*)
- We implement two use cases
  - A retention time distribution test
  - An experiment to validate two **latency reduction** mechanisms
- **SoftMC enables a wide range of studies**

Outline

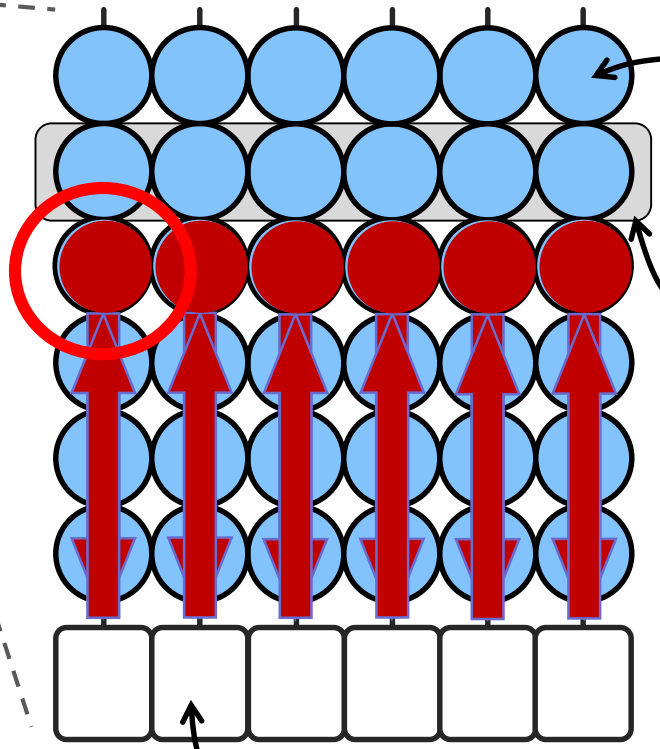
1. DRAM Basics & Motivation
2. SoftMC
3. Use Cases
   - Retention Time Distribution Study
   - Evaluating Recently-Proposed Ideas
4. Future Research Directions
5. Conclusion

DRAM Operations

Memory Bus

Precharge

CPU

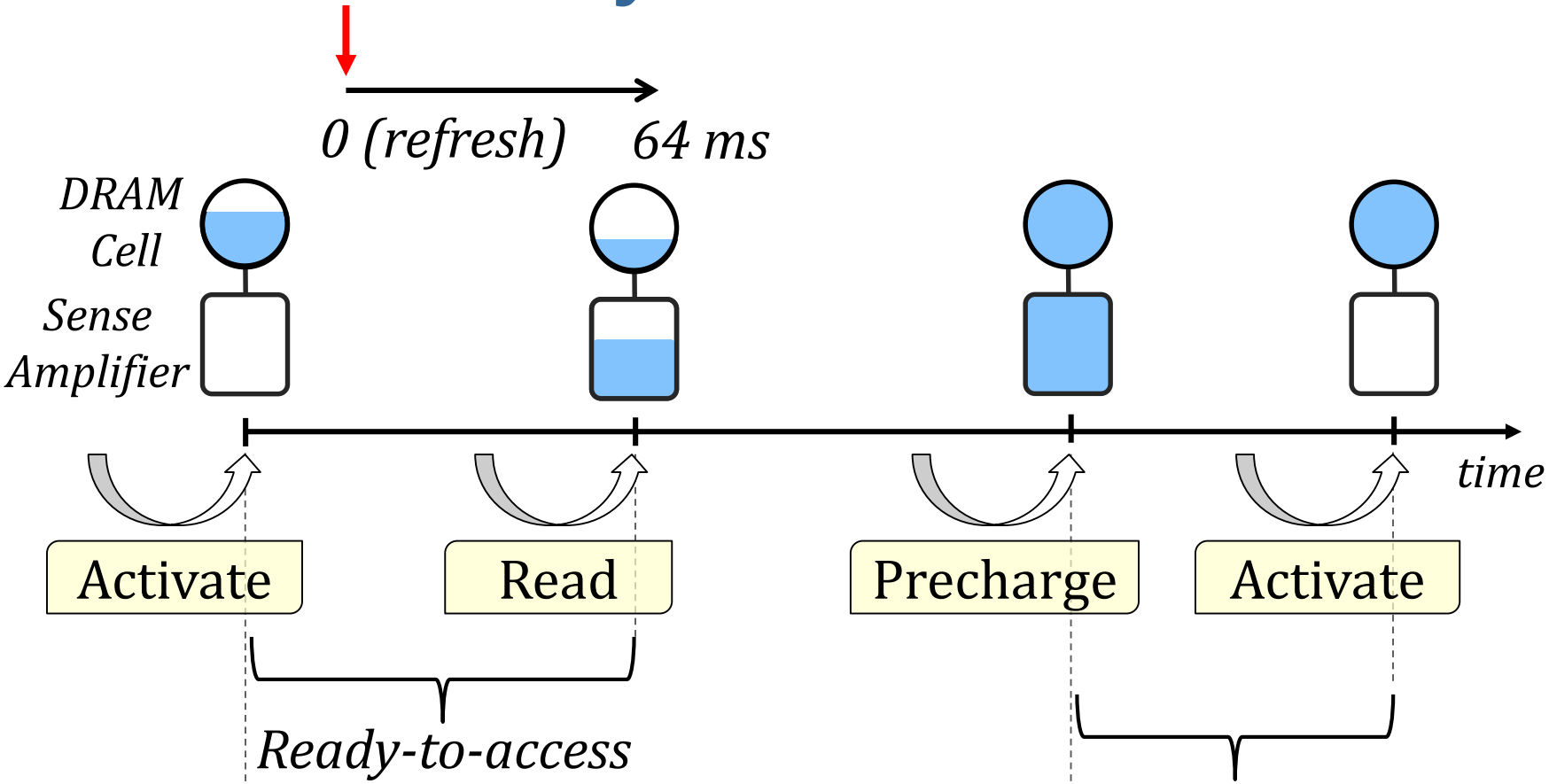


DRAM Cell

DRAM Row

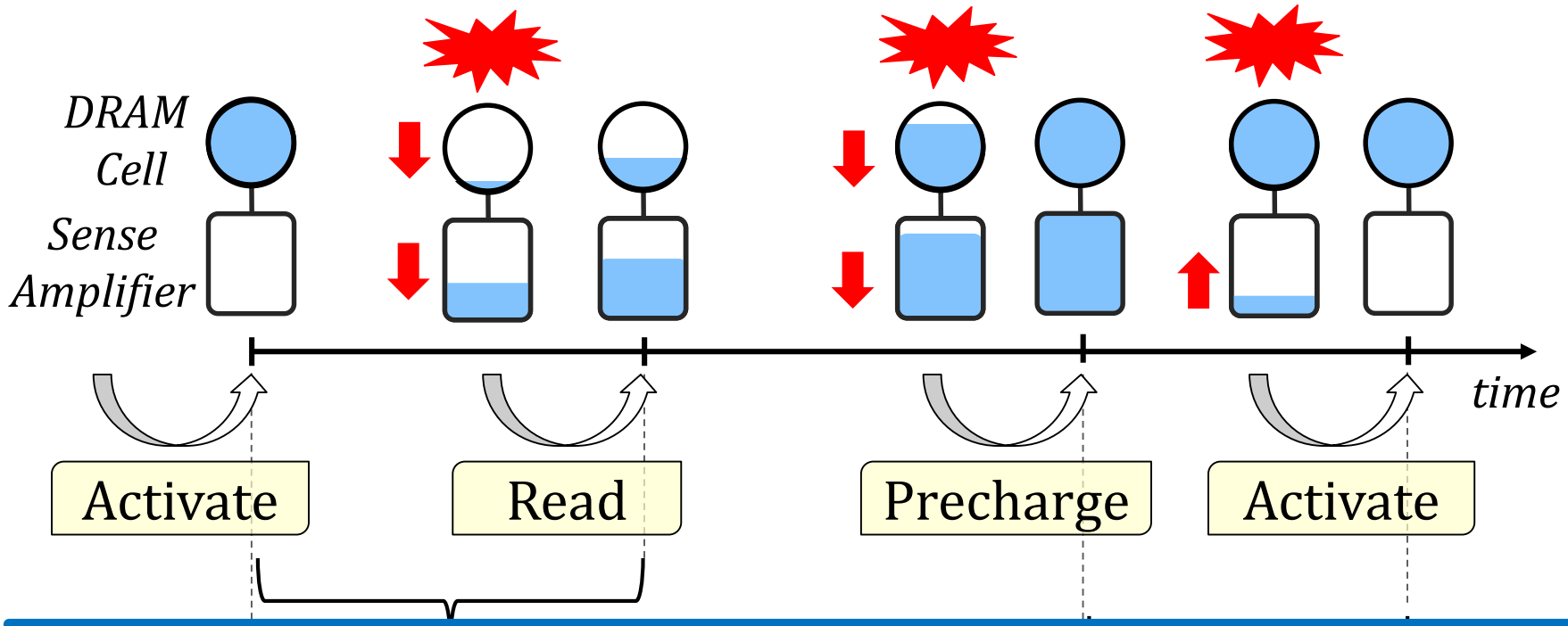
Sense Amplifier

DRAM Latency



Retention Time: The interval during which the data is retained correctly in the DRAM cell without accessing it

Latency vs. Reliability



Violating latencies negatively affects DRAM reliability

Other Factors Affecting Reliability and Latency

- Temperature
- Voltage
- Inter-cell Interference

To develop new mechanisms improving reliability and latency, we need to better understand the effects of these factors

Characterizing DRAM

Many of the factors
affecting DRAM reliability and latency
cannot be properly modeled

We need to perform
experimental studies
of *real* DRAM chips

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Goals of a DRAM Testing Infrastructure

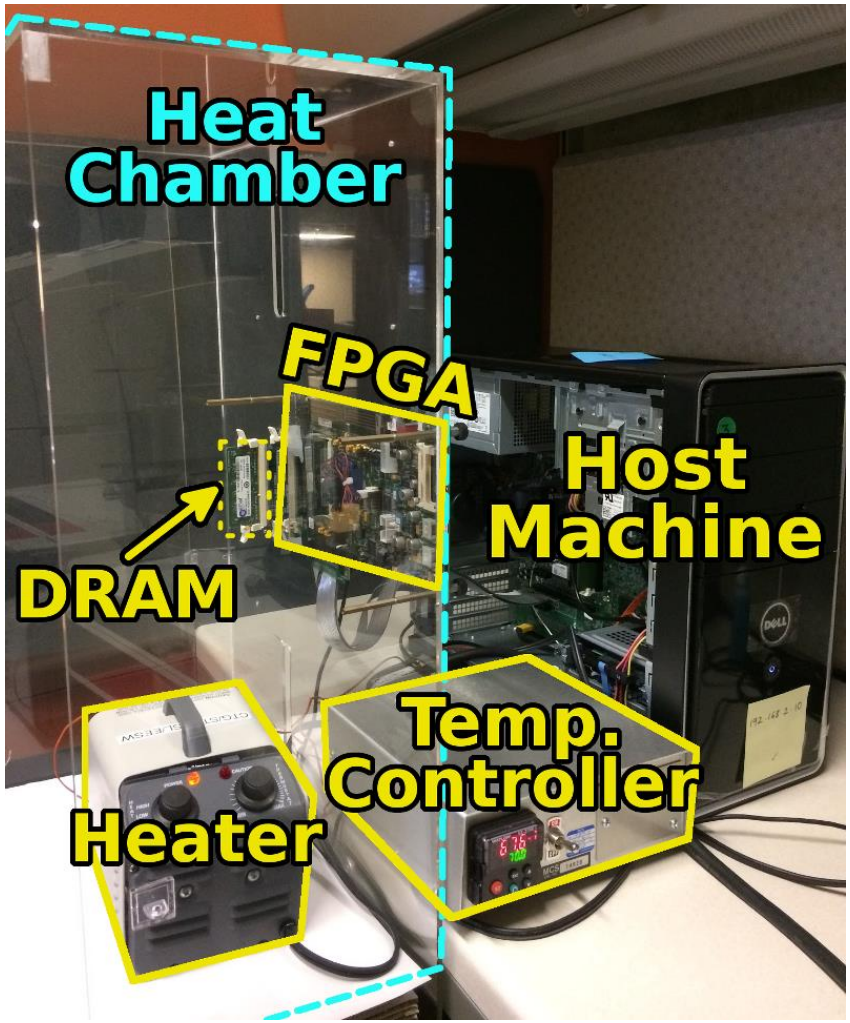
- Flexibility
  - Ability to test *any* DRAM operation
  - Ability to test *any* combination of DRAM operations and *custom* timing parameters
- Ease of use
  - Simple programming interface (C++)
  - Minimal programming effort and time
  - Accessible to a wide range of users
    - *who may lack experience in hardware design*

SoftMC: High-level View

FPGA-based
memory characterization
infrastructure

Prototype using *Xilinx ML605*

Easily programmable using
the C++ API



SoftMC: Key Components

1. SoftMC API

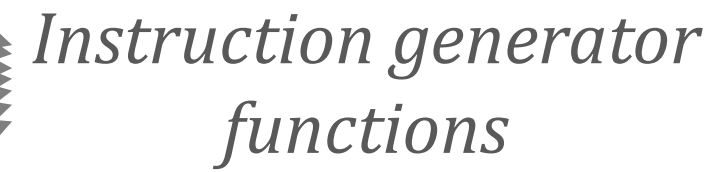
2. PCIe Driver

3. SoftMC Hardware

SoftMC API

Writing data to DRAM:

```
InstructionSequence iseq;
iseq.insert(genACT(bank, row));
iseq.insert(genWAIT(tRCD));
iseq.insert(genWR(bank, col, data));
iseq.insert(genWAIT(tCL + tBL + tWR));
iseq.insert(genPRE(bank));
iseq.insert(genWAIT(tRP));
iseq.insert(genEND());
iseq.execute(fpga);
```



SoftMC: Key Components

1. SoftMC API

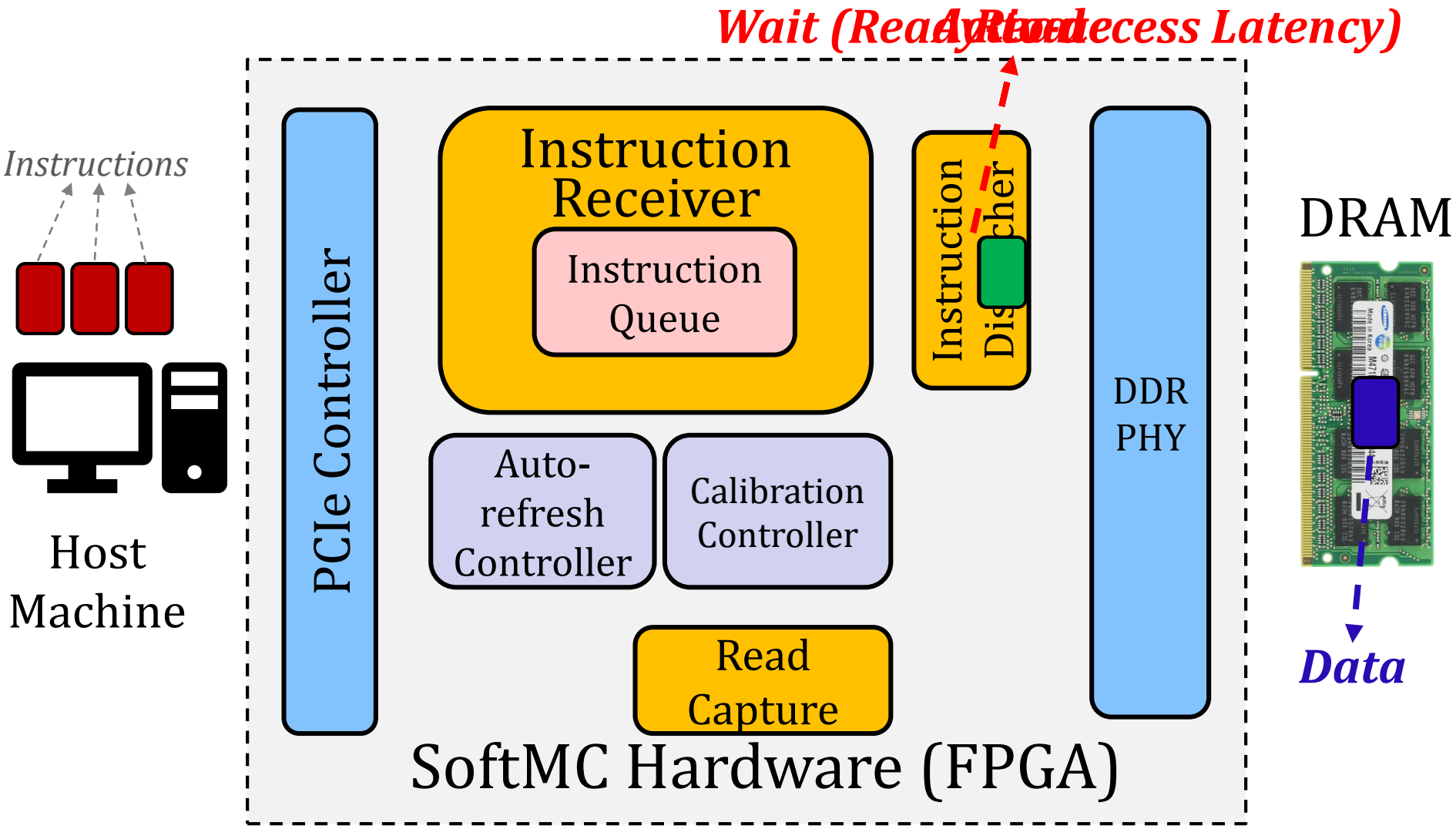
2. PCIe Driver*

- Communicates raw data with the FPGA

3. SoftMC Hardware

** Jacobsen, Matthew, et al. "RIFFA 2.1: A reusable integration framework for FPGA accelerators." TRETS, 2015*

SoftMC Hardware



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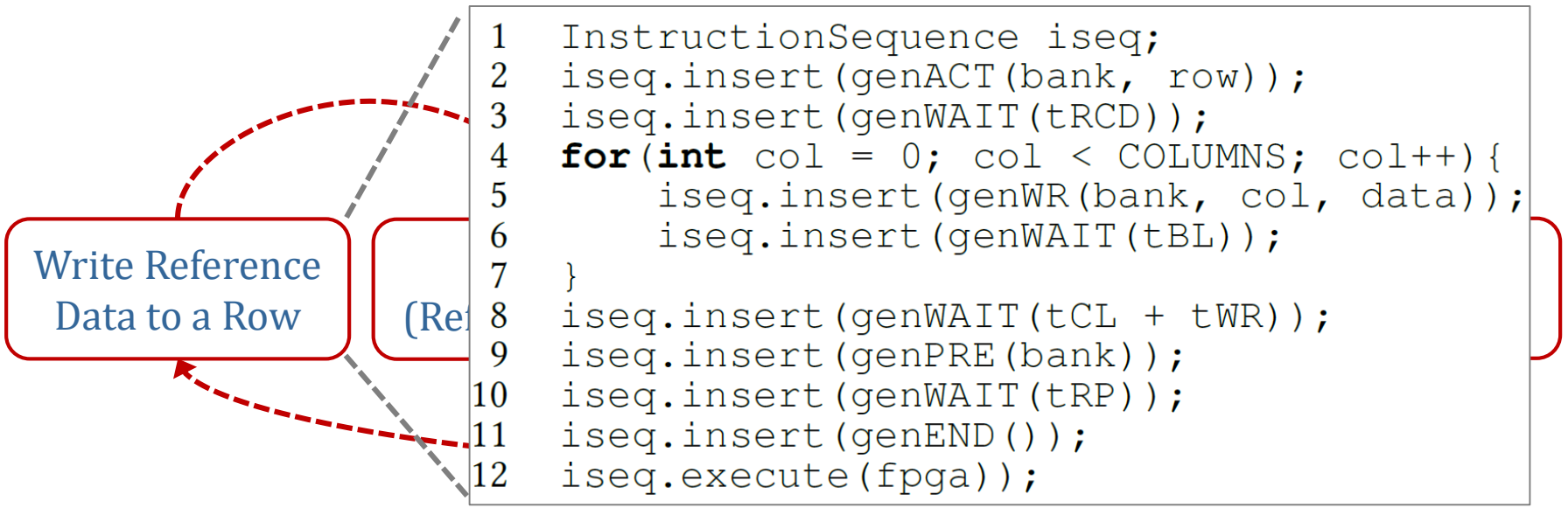
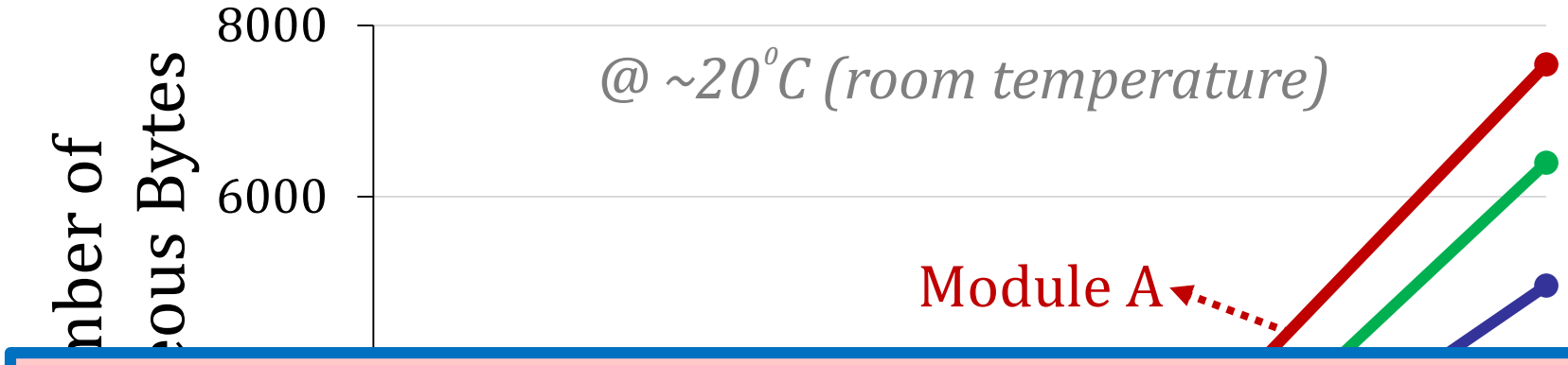
Retention Time Distribution Study




```
1   InstructionSequence iseq;
2   iseq.insert(genACT(bank, row));
3   iseq.insert(genWAIT(tRCD));
4   for(int col = 0; col < COLUMNS; col++){
5       iseq.insert(genWR(bank, col, data));
6       iseq.insert(genWAIT(tBL));
7   }
8   iseq.insert(genWAIT(tCL + tWR));
9   iseq.insert(genPRE(bank));
10  iseq.insert(genWAIT(tRP));
11  iseq.insert(genEND());
12  iseq.execute(fpga));
```

Can be implemented with just ~100 lines of code

Retention Time Test: Results



Validates the correctness of the SoftMC Infrastructure

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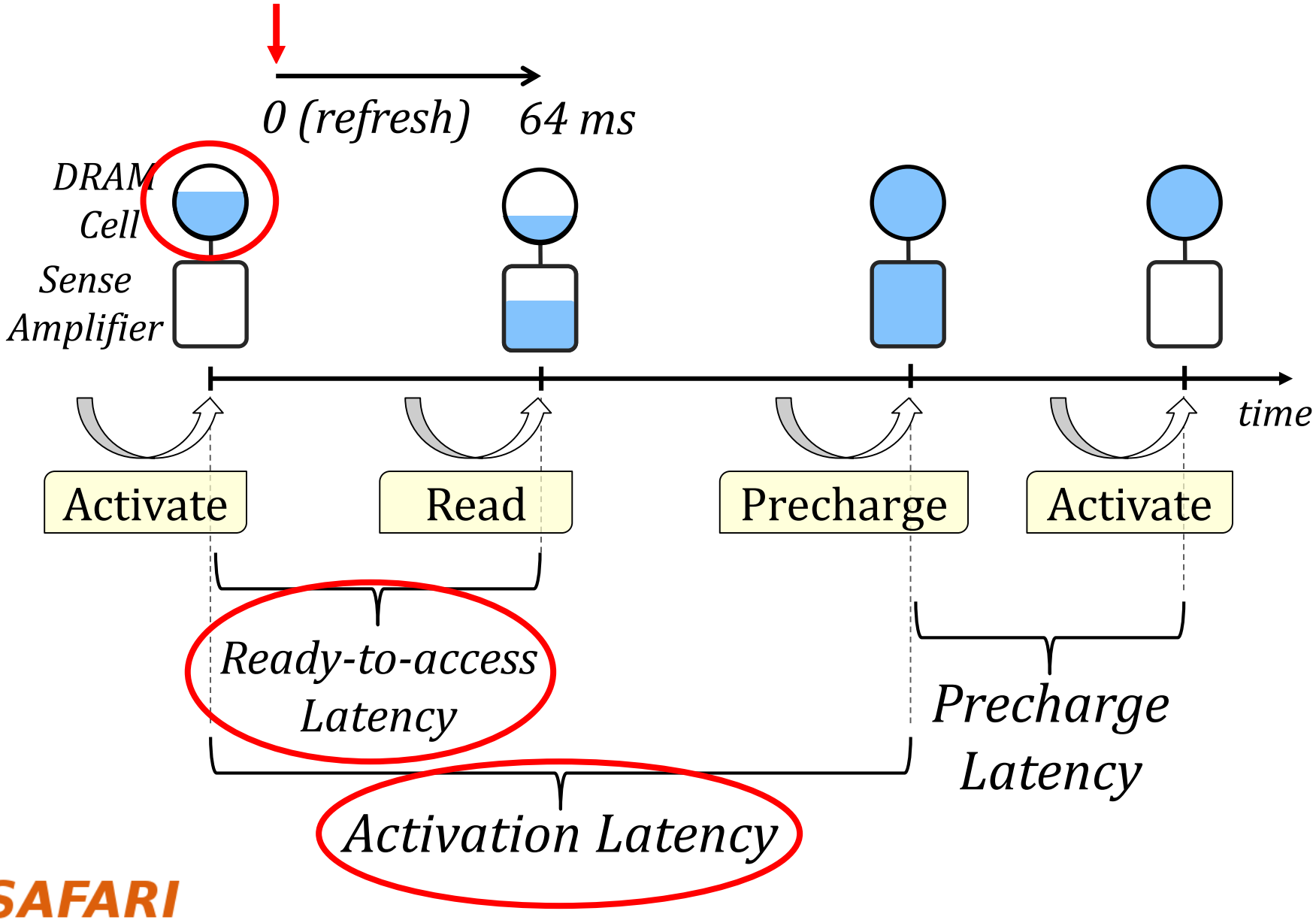
Accessing Highly-charged Cells Faster

NUAT
(Shin+, HPCA 2014)

ChargeCache
(Hassan+, HPCA 2016)

A highly-charged cell can be accessed with low latency

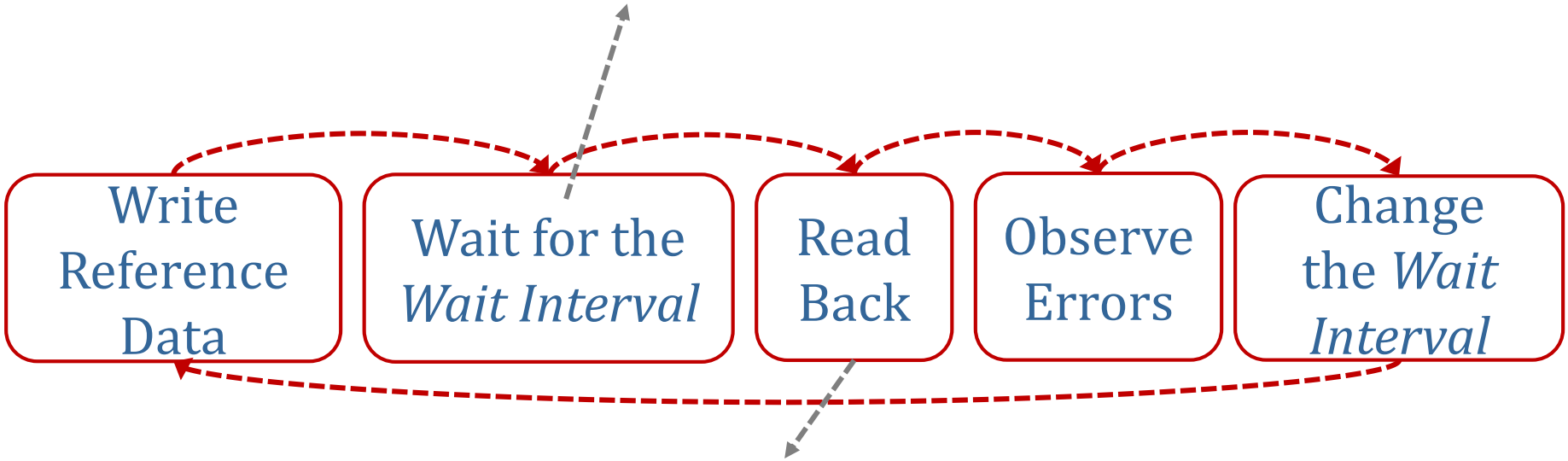
How a Highly-Charged Cell Is Accessed Faster?



Ready-to-access Latency Test

Longer wait ⇒ Lower cell charge

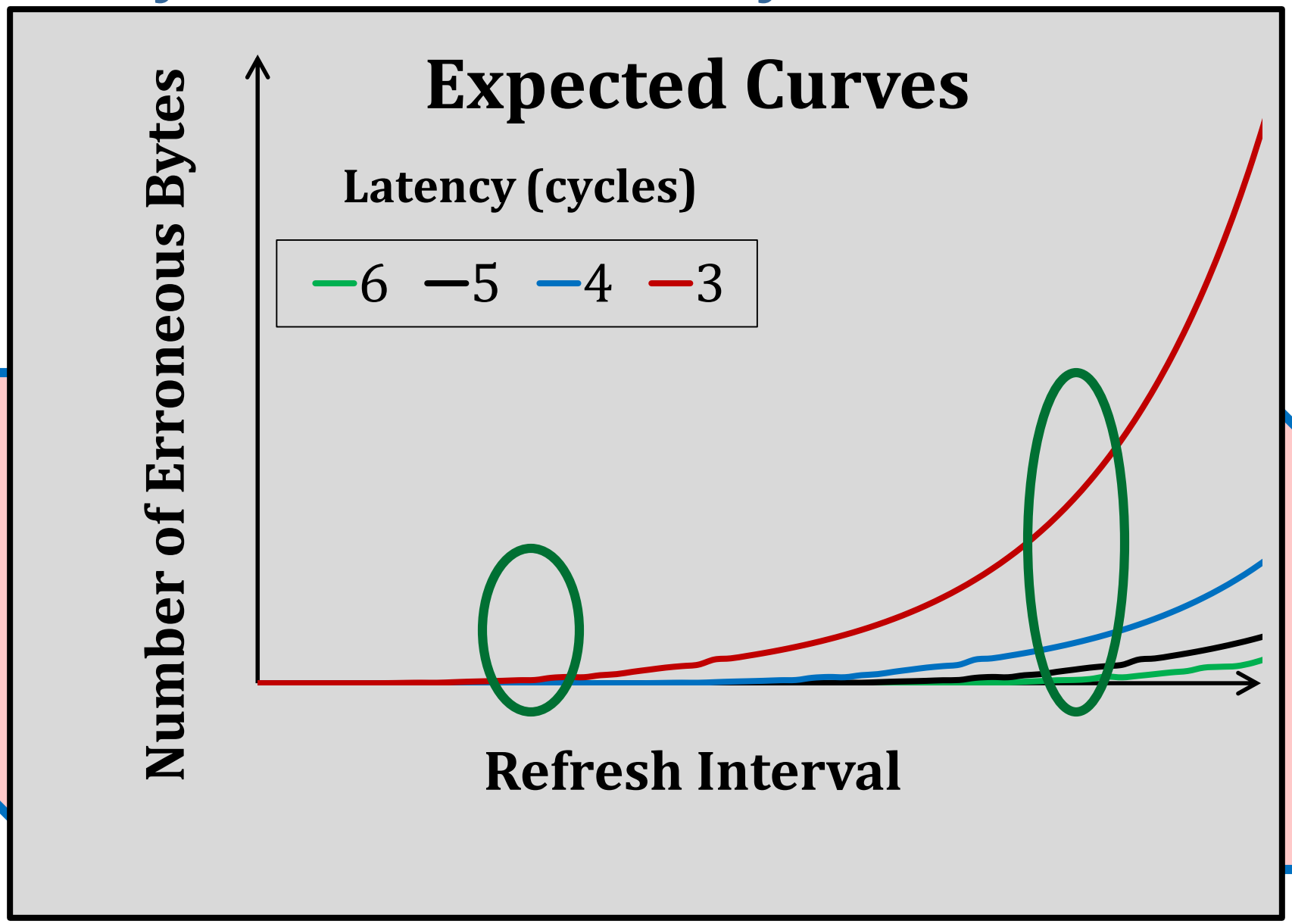
Shorter wait ⇒ Higher cell charge



With **custom** ready-to-access latency parameter

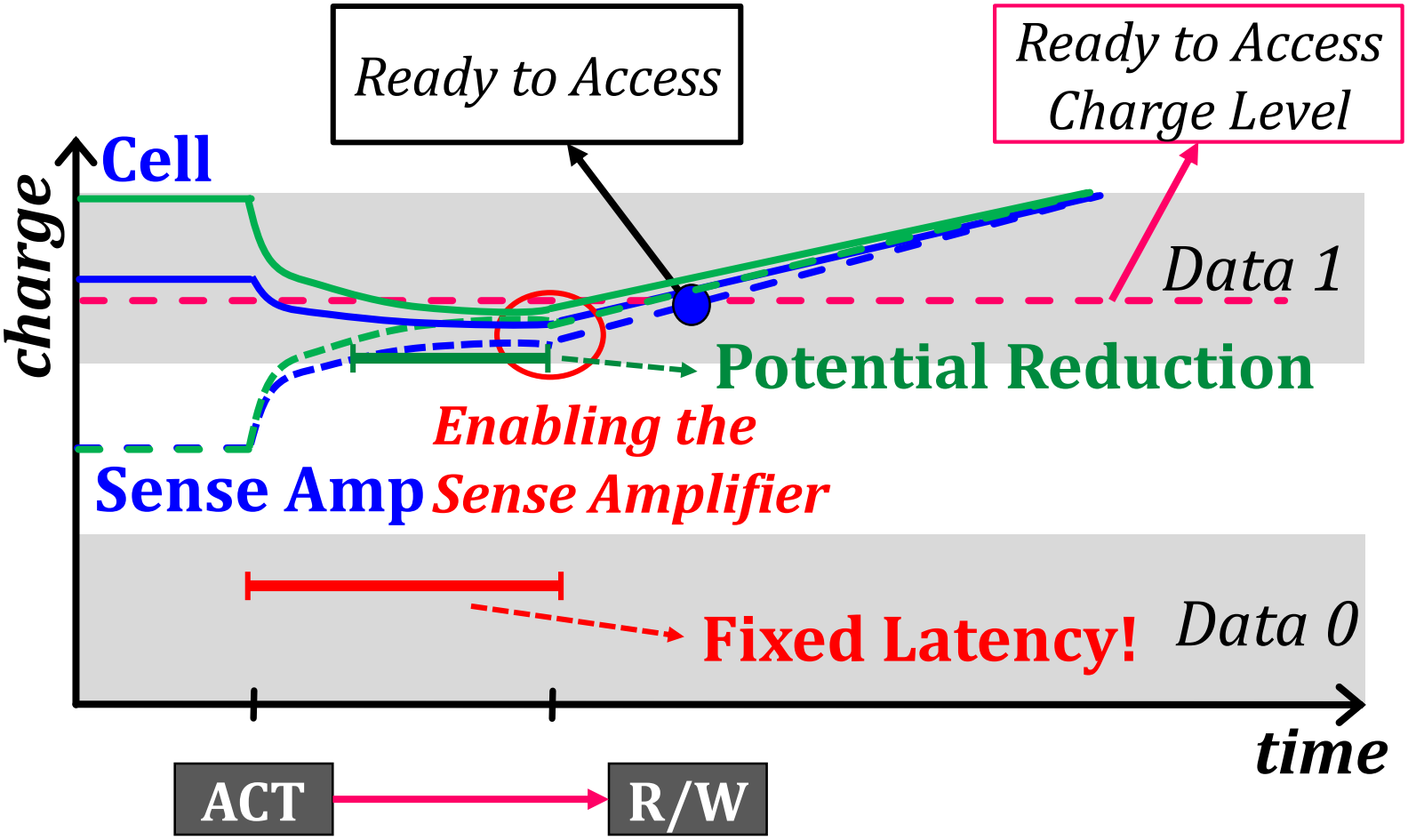
Can be implemented with just ~150 lines of code

Ready-to-access Latency: Results



Why Don't We See the Latency Reduction Effect?

- The memory controller cannot externally control when a sense amplifier gets enabled in existing DRAM chips



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Future Research Directions

- More Characterization of DRAM
  - How are the cell characteristics changing with different generations of technology nodes?
  - What types of usage accelerate aging?
- Characterization of Non-volatile Memory
- Extensions
  - Memory Scheduling
  - Workload Analysis
  - Testbed for in-memory Computation

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Conclusion

- **SoftMC**: First publicly-available FPGA-based DRAM testing infrastructure
- Flexible and Easy to Use
- Implemented two use cases
  - Retention Time Distribution Study
  - Evaluation of two recently-proposed latency reduction mechanisms
- SoftMC can enable many other studies, ideas, and methodologies in the design of future memory systems
- **Download** our first prototype

github.com/CMU-SAFARI/SoftMC

SoftMC

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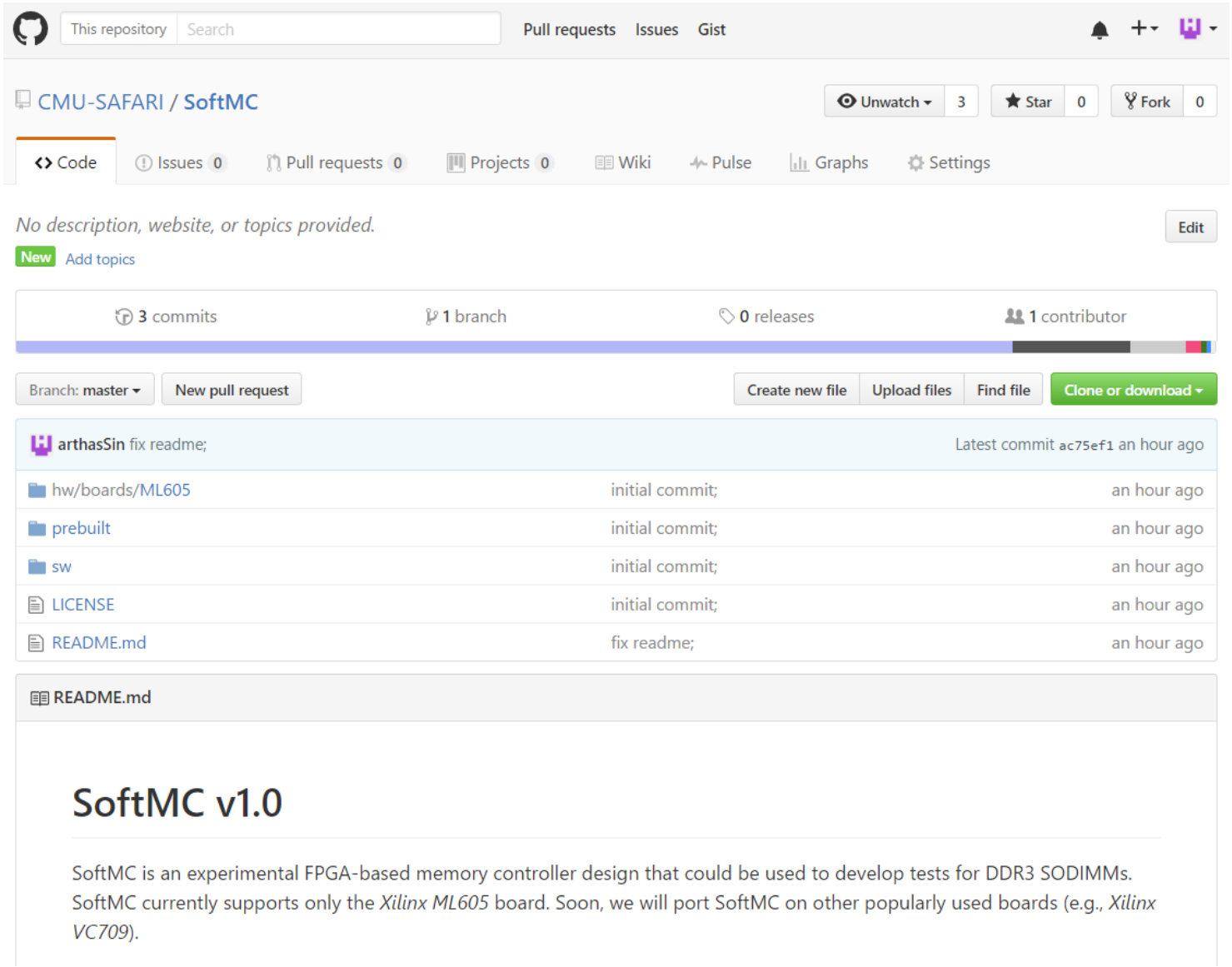
Backup Slides

Key SoftMC Instructions

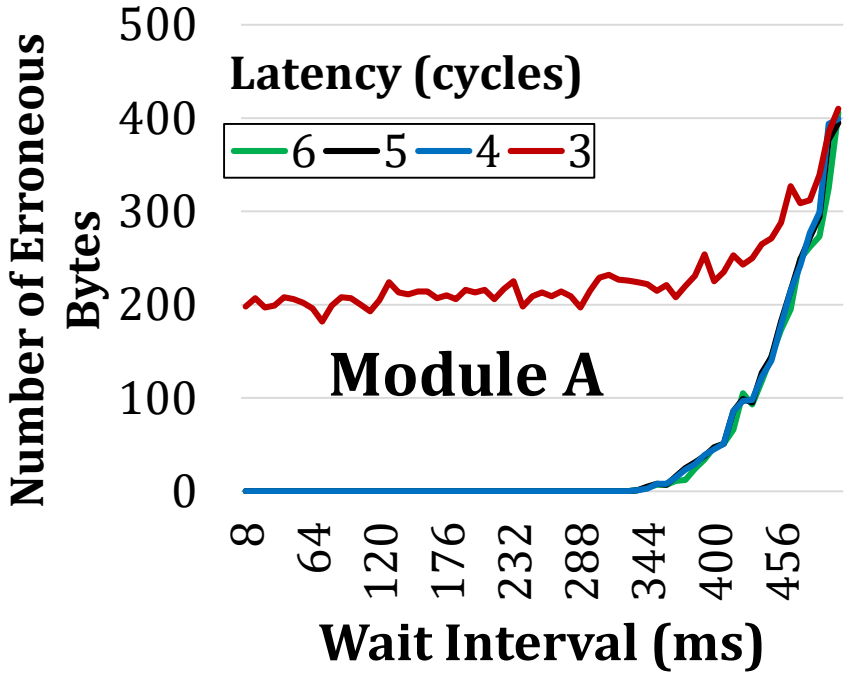
InstrType

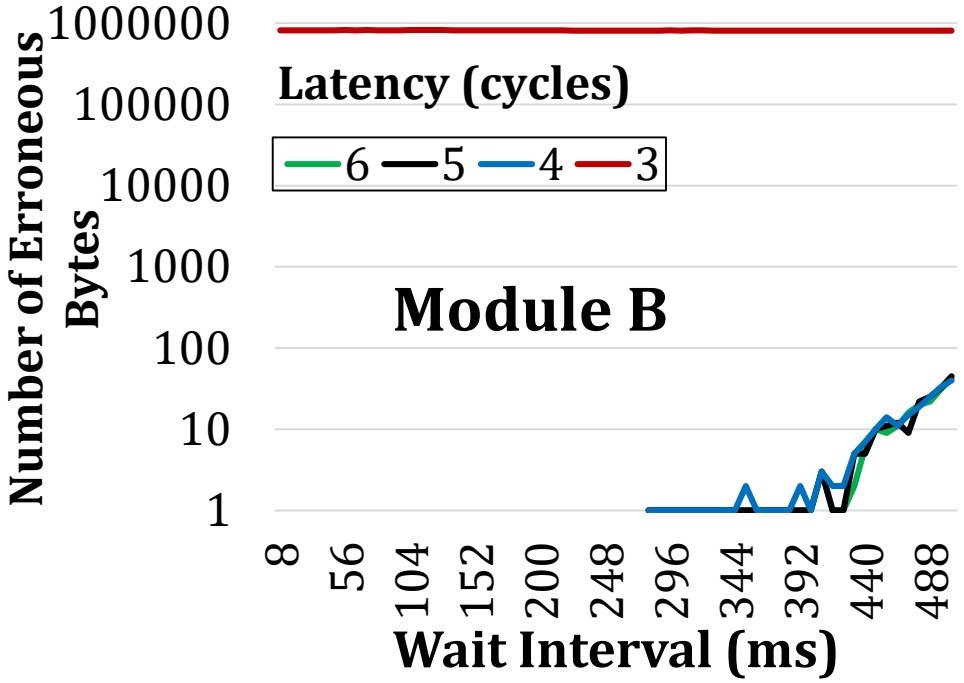
DDR (4)	*unused* (3)	CKE, CS (2), RAS, CAS, WE (6)	Bank (3)	Addr (16)
WAIT (4)	cycles (28)			
BUSDIR (4)	*unused* (27)			dir (1)
END (4)	*unused* (28)			

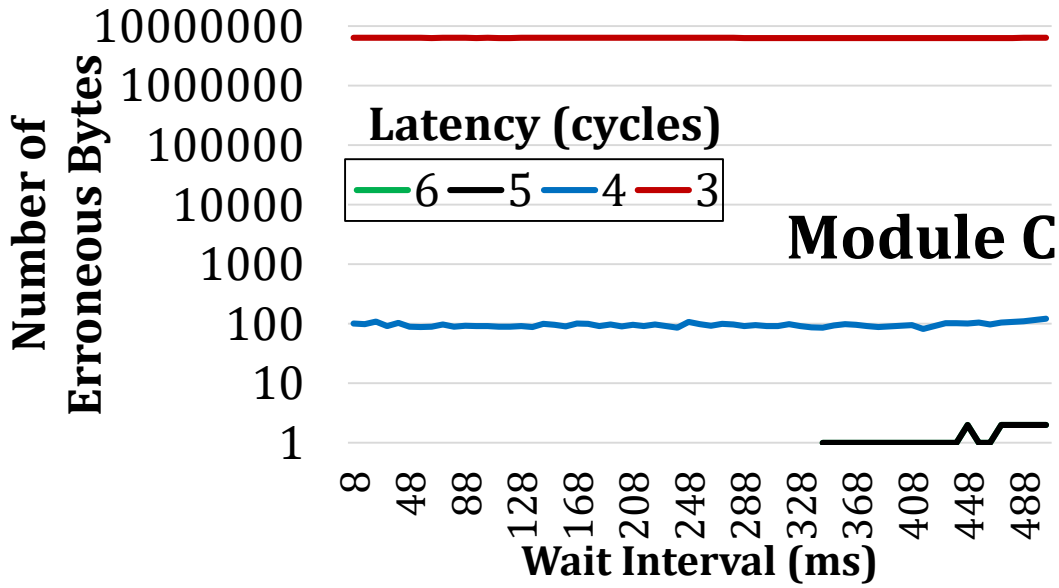
SoftMC @ Github



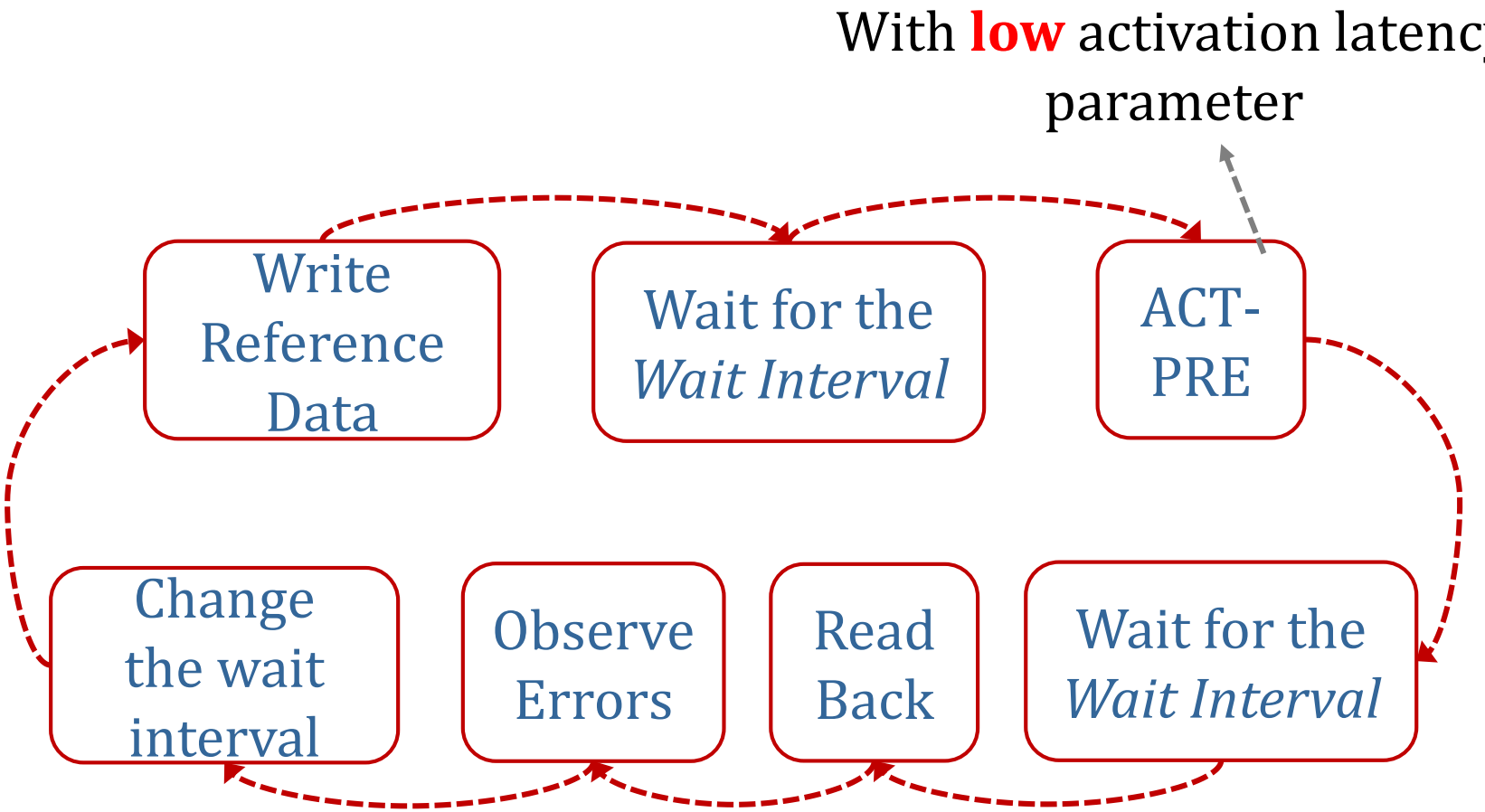
Ready-to-Access Latency Test Results







Activation Latency Test



Activation Latency Test Results